

Curriculum Vitae

Name: Dr. Gert Nolze

Date and place of birth: 26th July 1960, Sangerhausen

Address: Germanenstr. 49
12524 Berlin

Citizenship: German

Profession: Crystallographer

Position: Head of Working group "Local Phase Analysis"



Employment:

1986 - 1990	University of Leipzig, Crystallographic Institute
1990 - 1991	Central Institute for Physical Chemistry, Academy of Science, Berlin
1992 - 2008	Federal Institute for Materials Research and Testing (BAM), Berlin
2008 - 2011	Bruker Nano, Berlin

Degrees:

1986	M.Sc.	Crystallographic institute, University of Leipzig
1991	Ph.D.	Crystallographic institute, University of Leipzig

Positions held:

1986 - 1990	Research Assistant, Crystallographic institute, University of Leipzig,
1990 - 1991	Scientist, Central Institute for Physical Chemistry, Academy of Science, Berlin
1992 - 2002	Scientist, Federal Institute for Materials Research and Testing, Berlin
2002 - 2008	Team leader "Local Phase Analysis", Federal Institute for Materials Research and Testing, Berlin
2008 - 2011	Global Product Manager EBSD, Bruker Nano
2011 -	Team leader "Local Phase Analysis", Federal Institute for Materials Research and Testing, Berlin

Stay abroad:

1988:	4 month research stage in materials science, in Electrotechnical Institute, Leningrad
2000:	3 month fellowship in materials science, Japanese Fine Ceramic Center, Nagoya, Japan

Memberships: German Crystallographic Society

List of most important publications:

W. Kraus and G. Nolze,
POWDER CELL - a program for the representation and manipulation of crystal structures
and calculation of the resulting X-ray powder patterns,
J. Appl. Cryst., Vol. 29 (1996) pp. 301--303

G. Nolze,
Characterization of the fcc/bcc orientation relationship by EBSD using pole figures and
variants,
Z. Metallk., Vol. 95 (2004) pp. 744-755

G. Nolze, V. Geist, R. Saliwan Neumann and M. Buchheim,
Investigation of orientation relationships by EBSD and EDS on the example of the Watson
iron meteorite,
Cryst. Res. Technol., Vol. 40 (2005) pp. 791-804

G. Nolze,
Image distortions in SEM and their influences on EBSD measurements,
Ultramicroscopy, Vol. 107(2007) pp. 172-183

G. Nolze,
Irrational orientation relationship derived from rational orientation relationships using EBSD
data,
Cryst. Res. Technol., Vol. 43 (2008) pp. 61-73

A. Winkelmann and G. Nolze
Analysis of Kikuchi band contrast reversal in electron backscatter diffraction of silicon.
Ultramicroscopy, Vol. 110 (2010) pp. 190-194

G. Nolze
Azimuthal Projections : Data rotation and projection switching in real time.
Microsc. Microanal., Vol 19 (2013) pp. 950-958

E. Payton and G. Nolze
The backscatter electron signal as an additional tool for phase segmentation in electron
backscatter diffraction.
Microsc. Microanal., Vol. 19 (2013) pp. 929-941

G. Nolze,
Combination of colored patterns and cubes for crystallographic point group visualization.
Cryst. Res. Technol., Vol. 48 (2013) pp. 476-489